

Search Notes**Application/Control No.**

10/787,347

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

KIMURA, HAJIME

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	108	07.12.05	Hiep
	109	—	—
	110	—	—
326	82		
	83		
361	104		
315	109.3	↓	↓
330	292	↓	↓

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	07.12.05	Hiep
see attachment		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner